

Scanning Electron Microscope Photographs of the Alteration of Omphacite

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Wikström, A.: Scanning electron microscope photographs of the alteration of omphacite. *Norsk Geologisk Tidsskrift*, Vol. 51, pp. 191–192. Oslo 1971.

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In this journal an account has previously been given of the unmixing of omphacite in some Nordfjord eclogites (Wikström 1970). Additional information on the texture of the alteration product is given here with some scanning electron microscope photographs taken with an instrument at the Geological Survey of Sweden. The sample studied was collected from an eclogite body from Kjöde, Selje.

The finely polished specimen was held in HF vapour about one centimetre above the liquid for one minute. As can be seen from the photographs, the secondary pyroxene in the symplectite was strongly attacked using this procedure. The reason for the difference in etching capability between the unaltered omphacite and symplectite pyroxene is probably that crystal defects in the symplectite pyroxene have greatly increased its solubility.

General information about the photographs: dark areas with cleavage traces are omphacite; the light, weakly attacked areas are plagioclase and the strongly dissolved areas represent secondary pyroxene.

Picture number	Enlargement	Angle viewed from vertical position in degrees
1	135	30
2	1350	0
3	1300	45
4	3250	45
5	650	45
6	3500	68

REFERENCE

Wikström, A. 1970: Electron micro-probe studies of the alteration of omphacite in eclogites from the Nordfjord area, Norway. *Norsk geol. tidsskr.* 70, 137–156.

